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Software Reliability: Status and Perspectives

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Message from the Guest Editors

Software reliability has attracted an increasing amount of attention from the academic society and industrial communities in recent decades, especially against the background of the Industry 4.0 era, where software systems become more and more complex and are playing an increasingly important role in both the industrial world and our daily lives—for example, cyberphysical systems (CPS), Internet of Things (IoT) systems, real-time systems, and machine learning-based systems. The failures requirement violations of these systems may lead to disruptive or even catastrophic consequences, such as significant economic damage or the loss of human lives. Therefore, it is essential to maintain software reliability in the face of faults and failures, and as a result, the topic of software reliability has been extensively studied in recent decades. Nevertheless, software reliability keeps posing challenging research questions due to the complexity, heterogeneity, and distributivity of software systems.











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Message from the Editor-in-Chief

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